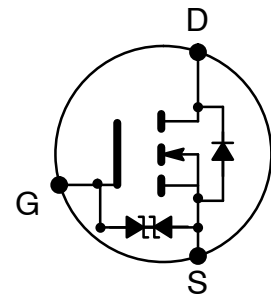




ELECTRONICS, INC.
 44 FARRAND STREET
 BLOOMFIELD, NJ 07003
 (973) 748-5089
<http://www.nteinc.com>

**NTE2948
 MOSFET
 N-Channel, Enhancement Mode
 High Speed Switch
 TO251 Type Package**



Features:

- Low Drain-Source ON Resistance: $R_{DS(ON)} = 4\Omega$ (Typ)
- High Forward Transfer Admittance: $|y_{fs}| = 0.6S$ (Typ)
- Low Leakage Current: $I_{DSS} = 100\mu A$ (Max) ($V_{DS} = 400V$)
- Enhancement Model: $V_{th} = 2$ to $4V$ ($V_{DS} = 10V, I_D = 1mA$)

Applications:

- DC-DC Converter
- Relay Drive
- Motor Drive

Absolute Maximum Ratings: ($T_A = +25^\circ C$ unless otherwise specified)

Drain-Source Voltage, V_{DSS}	400V
Drain-Gate Voltage ($R_{GS} = 20k\Omega$), V_{DGR}	400V
Gate-Source Voltage, V_{GS}	$\pm 30V$
Drain Current (Note 1), I_D	
DC	1A
Pulsed	3A
Drain Power Dissipation ($T_C = +25^\circ C$), P_D	20W
Single Pulsed Avalanche Energy (Note 2), E_{AS}	113mJ
Avalanche Current, I_{AR}	1A
Repetitive Avalanche Energy (Note 3), E_{AR}	2mJ
Channel Temperature, T_{ch}	$+150^\circ C$
Storage Temperature Range, T_{stg}	$-55^\circ C$ to $+150^\circ C$
Maximum Thermal Resistance:	
Channel-to-Case, R_{thCHC}	$6.25^\circ C/W$
Channel-to-Ambient, R_{thCHA}	$125^\circ C/W$

- Note 1. Please use devices on condition that the channel temperature is below $+150^\circ C$.
 Note 2. $V_{DD} = 90V, T_{ch} = +25^\circ C$ (initial), $L = 183mH, R_G = 25\Omega$.
 Note 3. Repetitive rating: pulse width limited by maximum channel temperature.



Electrical Characteristics: ($T_A = +25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Gate–Source Leakage Current	I_{GSS}	$V_{GS} = \pm 25\text{V}, V_{DS} = 0\text{V}$	–	–	± 10	μA
Gate–Source Breakdown Voltage	BV_{GSS}	$I_G = \pm 10\mu\text{A}, V_{DS} = 0\text{V}$	± 30	–	–	V
Drain Cutoff Current	I_{DSS}	$V_{DS} = 400\text{V}, V_{GS} = 0$	–	–	100	μA
Drain–Source Breakdown Voltage	BV_{DSS}	$I_D = 10\text{mA}, V_{GS} = 0\text{V}$	480	–	–	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = 10\text{V}, I_D = 1\text{mA}$	2.0	–	4.0	V
Drain–Source ON Resistance	$R_{DS(on)}$	$V_{GS} = 10\text{V}, I_D = 0.5\text{A}$	–	4.2	5.5	Ω
Forward Transfer Admittance	$ y_{fs} $	$V_{DS} = 10\text{V}, I_D = 0.5\text{A}$	0.3	0.6	–	S
Input Capacitance	C_{iss}	$V_{GS} = 0\text{V}, V_{DS} = 10\text{V}, f = 1\text{MHz}$	–	145	–	pF
Output Capacitance	C_{oss}		–	80	–	pF
Reverse Transfer Capacitance	C_{rss}		–	35	–	pF
Turn–On Delay Time	$t_{d(on)}$	$V_{DD} = 200\text{V}, V_{GS} = 10\text{V}, I_D = 0.5\text{A}, R_L = 400\Omega, \text{Duty} \leq 1\%, t_w = 10\mu\text{s}$	–	56	–	ns
Rise Time	t_r		–	14	–	ns
Turn–Off Delay Time	$t_{d(off)}$		–	75	–	ns
Fall Time	t_f		–	26	–	ns
Total Gate Charge	Q_g	$V_{GS} = 10\text{V}, I_D = 1\text{A}, V_{DD} = 320\text{V}$	–	5.7	–	nC
Gate–Source Charge	Q_{gs}		–	3.0	–	nC
Gate–Drain (“Miller”) Charge	Q_{gd}		–	2.7	–	nC
Source–Drain Diode Ratings and Characteristics						
Continuous Drain Reverse Current	I_{DR}	Note 1	–	–	1	A
Pulse Drain Reverse Current	I_{DRP}	Note 1	–	–	3	A
Diode Forward Voltage	V_{SDF}	$I_{DR} = 1\text{A}, V_{GS} = 0\text{V}$	–	–	–1.7	V
Reverse Recovery Time	t_{rr}	$I_{DR} = 1\text{A}, V_{GS} = 0\text{V}, dI_{DR}/dt = 100\text{A}/\mu\text{s}$	–	650	–	ns
Reverse Recovery Charge	Q_{rr}		–	14.6	–	μC

Note 1. Please use devices on condition that the channel temperature is below $+150^\circ\text{C}$.

